

TIBPAL20L8-5C, TIBPAL20R4-5C, TIBPAL20R6-5C, TIBPAL20R8-5C
TIBPAL20L8-7M, TIBPAL20R4-7M, TIBPAL20R6-7M, TIBPAL20R8-7M
HIGH-PERFORMANCE *IMPACT-X*TM PAL[®] CIRCUITS

SRPS010F – D3353, OCTOBER 1989 – REVISED SEPTEMBER 1992

- **High-Performance Operation:**
 - f_{max} (no feedback)
 - TIBPAL20R' -5C Series . . . 125 MHz Min
 - TIBPAL20R' -7M Series . . . 100 MHz Min
 - f_{max} (internal feedback)
 - TIBPAL20R' -5C Series . . . 125 MHz Min
 - TIBPAL20R' -7M Series . . . 100 MHz Min
 - f_{max} (external feedback)
 - TIBPAL20R' -5C Series . . . 117 MHz Min
 - TIBPAL20R' -7M Series . . . 74 MHz Min
 - Propagation Delay**
 - TIBPAL20L8-5C Series . . . 5 ns Max
 - TIBPAL20L8-7M Series . . . 7 ns Max
 - TIBPAL20R' -5C Series (CLK-to-Q) . . . 4 ns Max
 - TIBPAL20R' -7M Series (CLK-to-Q) . . . 6.5 ns Max

- **Functionally Equivalent, but Faster Than, Existing 24-Pin PLDs**
- **Preload Capability on Output Registers Simplifies Testing**
- **Power-Up Clear on Registered Devices (All Register Outputs are Set Low, but Voltage Levels at the Output Pins Go High)**
- **Package Options Include Both Plastic and Ceramic Chip Carriers in Addition to Plastic and Ceramic DIPs**
- **Security Fuse Prevents Duplication**

DEVICE	I INPUTS	3-STATE O OUTPUTS	REGISTERED Q OUTPUTS	I/O PORTS
PAL20L8	14	2	0	6
PAL20R4	12	0	4 (3-state buffers)	4
PAL20R6	12	0	6 (3-state buffers)	2
PAL20R8	12	0	8 (3-state buffers)	0

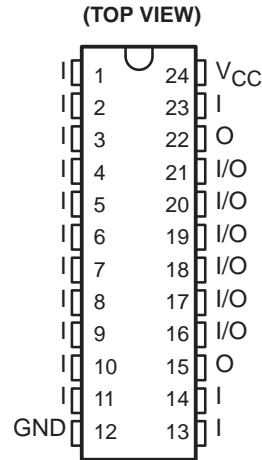
description

These programmable array logic devices feature high speed and functional equivalency when compared with currently available devices. These *IMPACT-X*TM circuits combine the latest Advanced Low-Power Schottky technology with proven titanium-tungsten fuses to provide reliable, high-performance substitutes for conventional TTL logic. Their easy programmability allows for quick design of custom functions and typically results in a more compact circuit board.

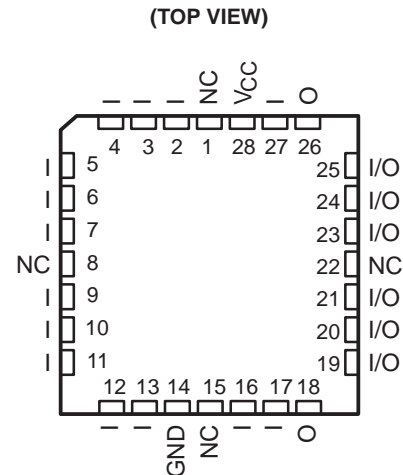
The TIBPAL20' C series is characterized from 0°C to 75°C. The TIBPAL20' M series is characterized for operation over the full military temperature range of -55°C to 125°C.

These devices are covered by U.S. Patent 4,410,987. *IMPACT-X* is a trademark of Texas Instruments Incorporated. PAL is a registered trademark of Advanced Micro Devices Inc.

TIBPAL20L8'
C SUFFIX . . . JT OR NT PACKAGE
M SUFFIX . . . JT PACKAGE



TIBPAL20L8'
C SUFFIX . . . FN PACKAGE
M SUFFIX . . . FK PACKAGE



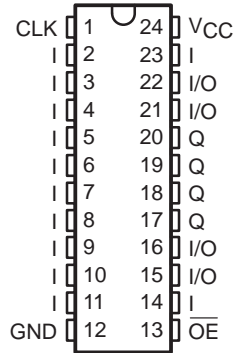
NC – No internal connection
 Pin assignments in operating mode

This document contains information on products in more than one phase of development. The status of each device is indicated on the page(s) specifying its electrical characteristics.

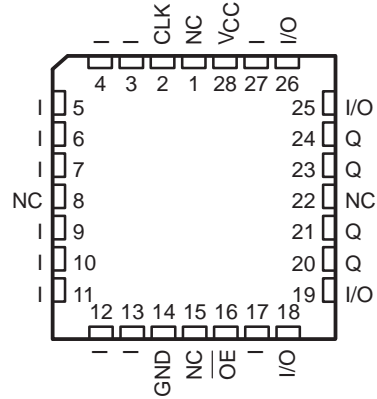


**TIBPAL20R4-5C, TIBPAL20R6-5C, TIBPAL20R8-5C
TIBPAL20R4-7M, TIBPAL20R6-7M, TIBPAL20R8-7M
HIGH-PERFORMANCE *IMPACT-X*™ *PAL*® CIRCUITS**
SRPS010F – D3353, OCTOBER 1989 – REVISED SEPTEMBER 1992

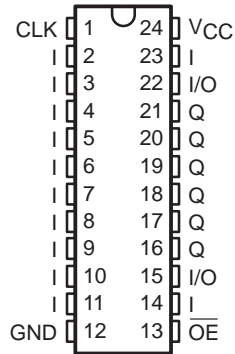
TIBPAL20R4'
C SUFFIX ... JT OR NT PACKAGE
M SUFFIX ... JT PACKAGE
(TOP VIEW)



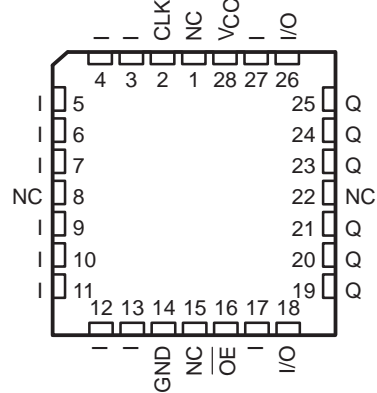
TIBPAL20R4'
C SUFFIX ... FN PACKAGE
M SUFFIX ... FK PACKAGE
(TOP VIEW)



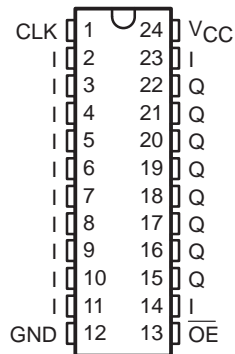
TIBPAL20R6'
C SUFFIX ... JT OR NT PACKAGE
M SUFFIX ... JT PACKAGE
(TOP VIEW)



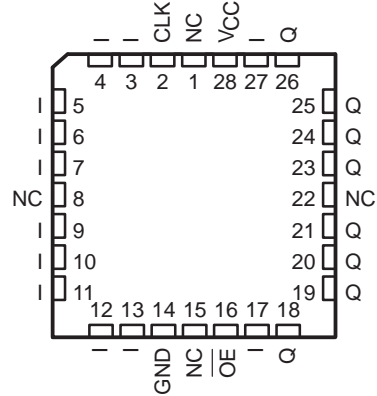
TIBPAL20R6'
C SUFFIX ... FN PACKAGE
M SUFFIX ... FK PACKAGE
(TOP VIEW)



TIBPAL20R8'
C SUFFIX ... JT OR NT PACKAGE
M SUFFIX ... JT PACKAGE
(TOP VIEW)



TIBPAL20R8'
C SUFFIX ... FN PACKAGE
M SUFFIX ... FK PACKAGE
(TOP VIEW)

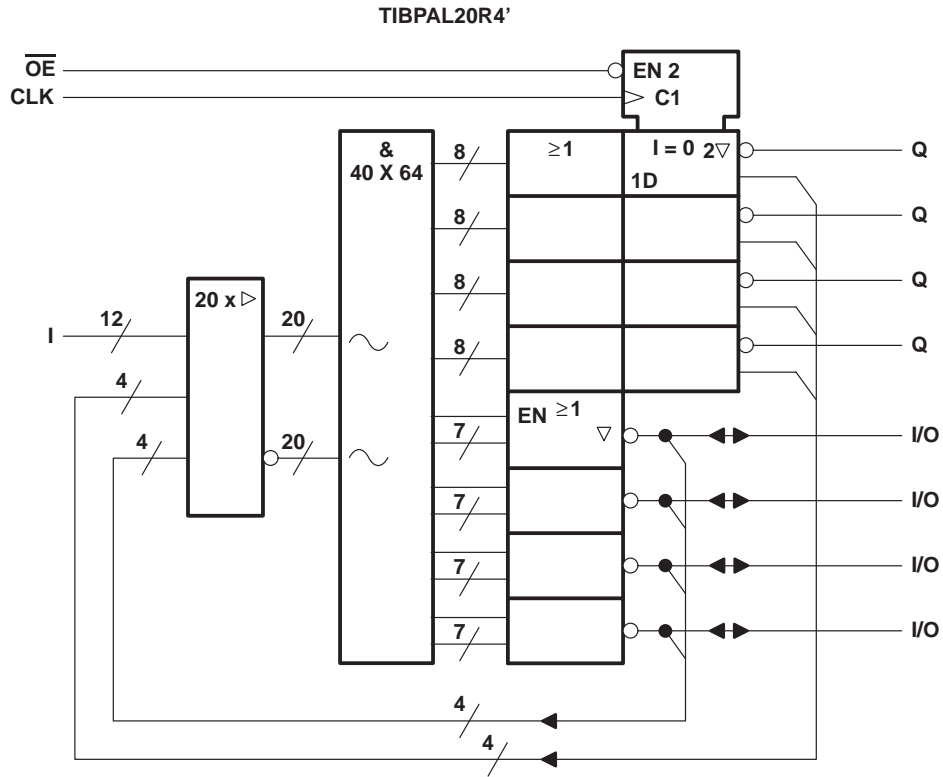
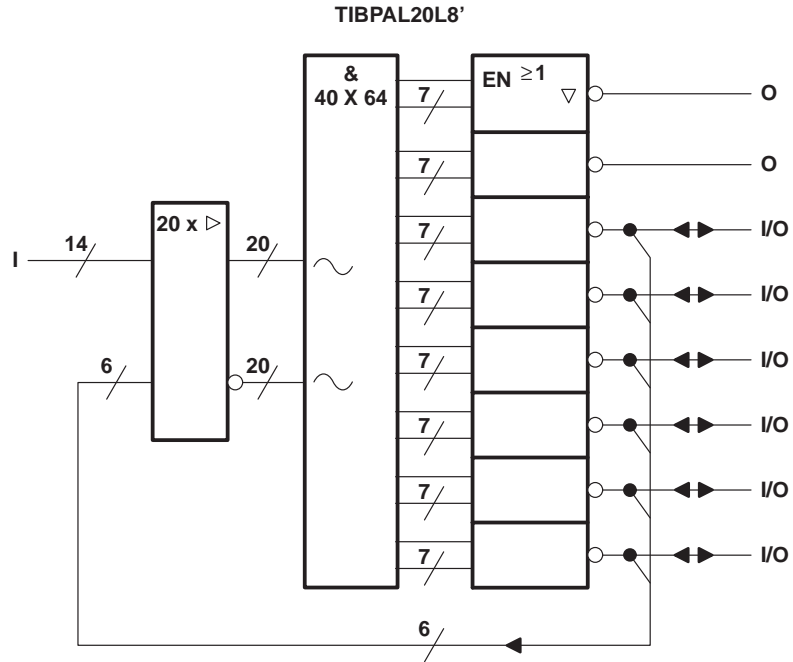


Pin assignments in operating mode

NC – No internal connection



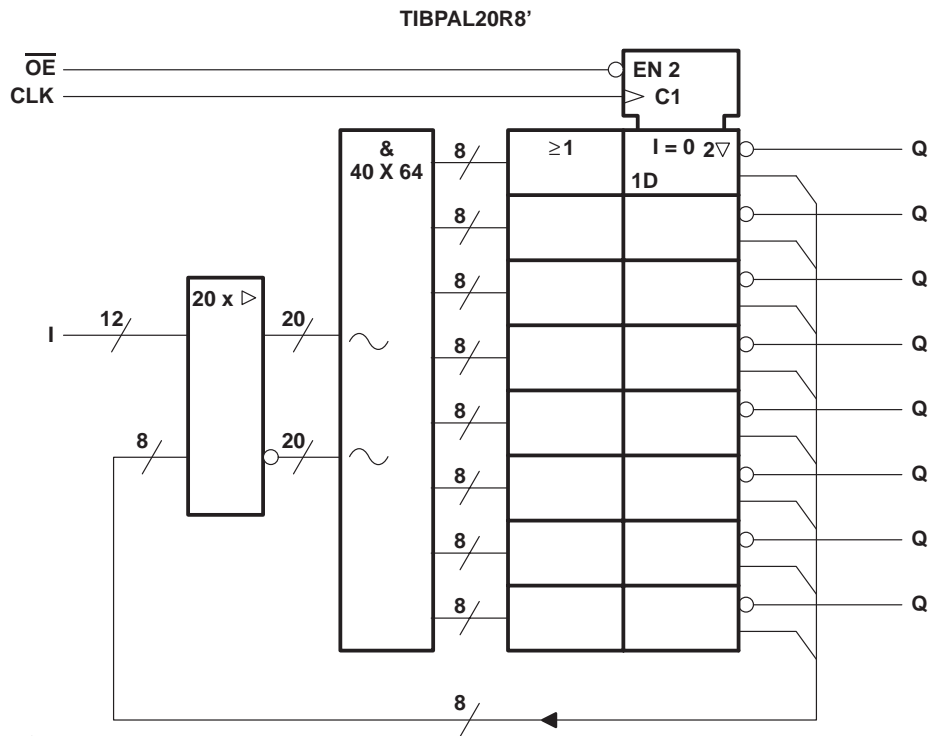
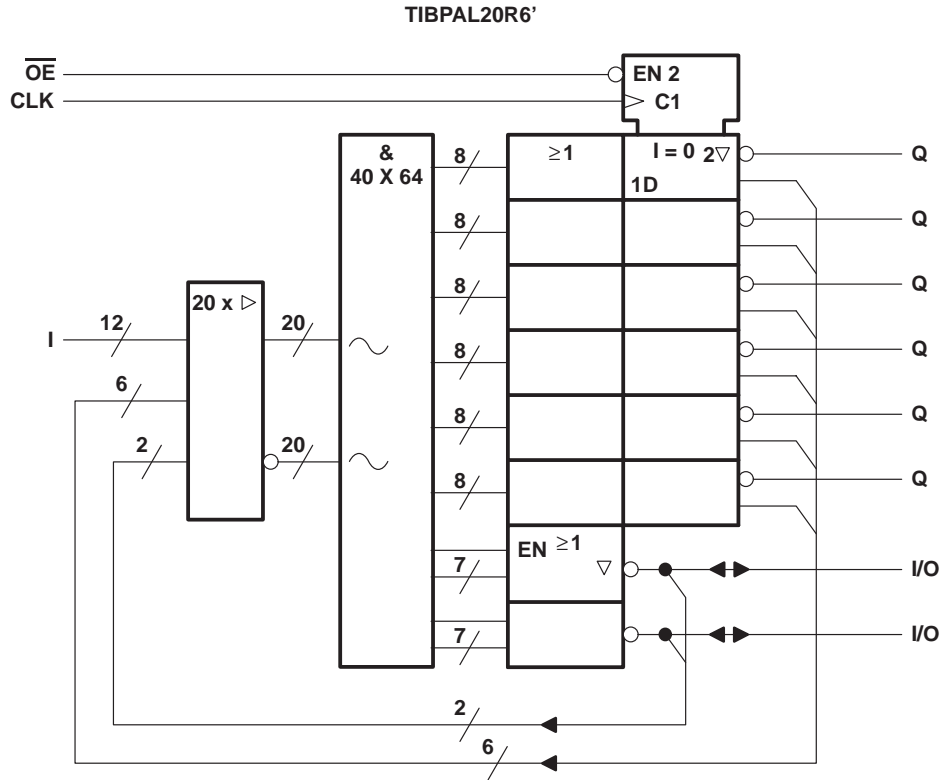
functional block diagrams (positive logic)



~ denotes fused inputs

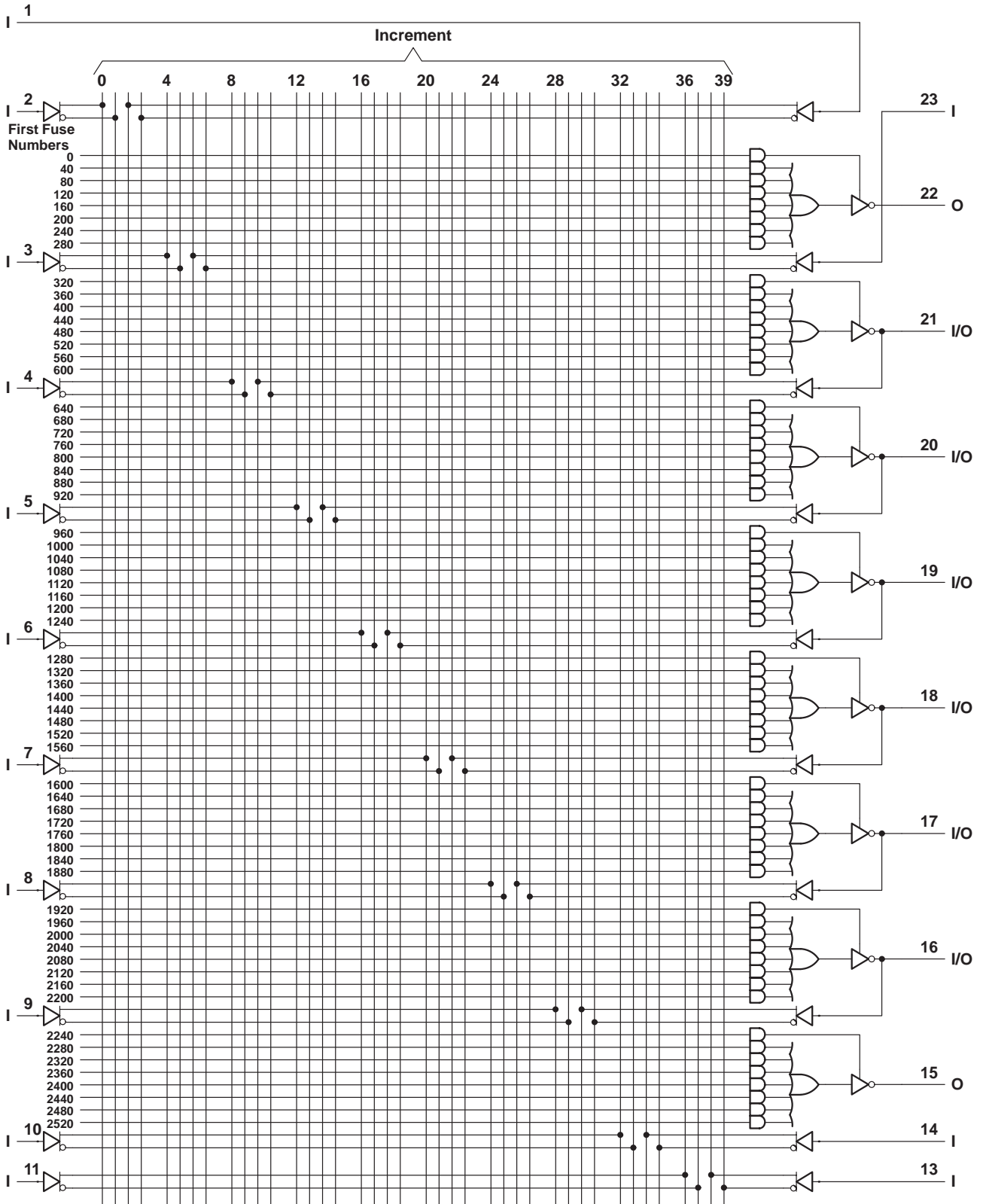
TIBPAL20R6-5C, TIBPAL20R8-5C
 TIBPAL20R6-7M, TIBPAL20R8-7M
 HIGH-PERFORMANCE *IMPACT-X*™ PAL® CIRCUITS
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functional block diagrams (positive logic)



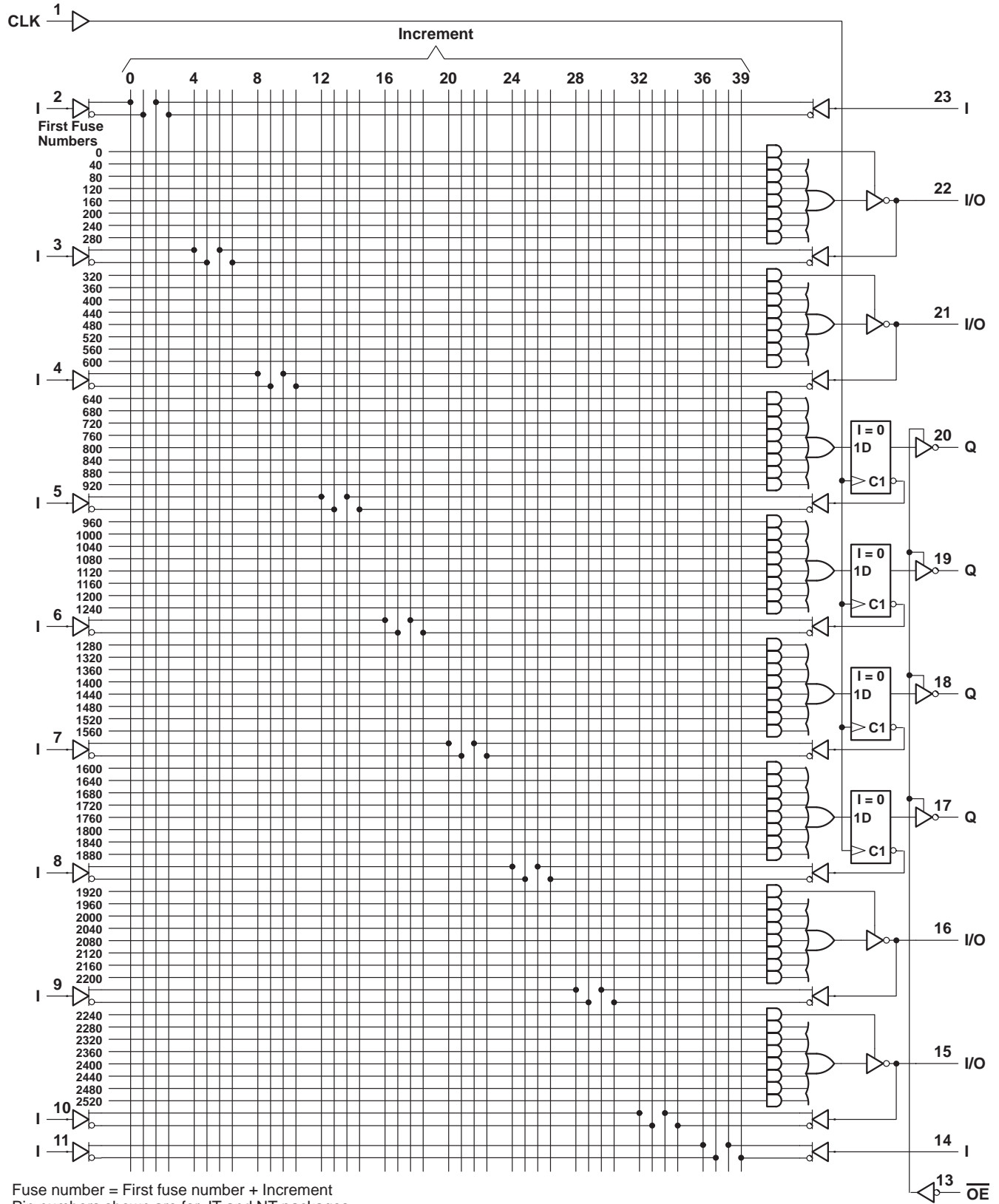
~ denotes fused inputs

logic diagram (positive logic)

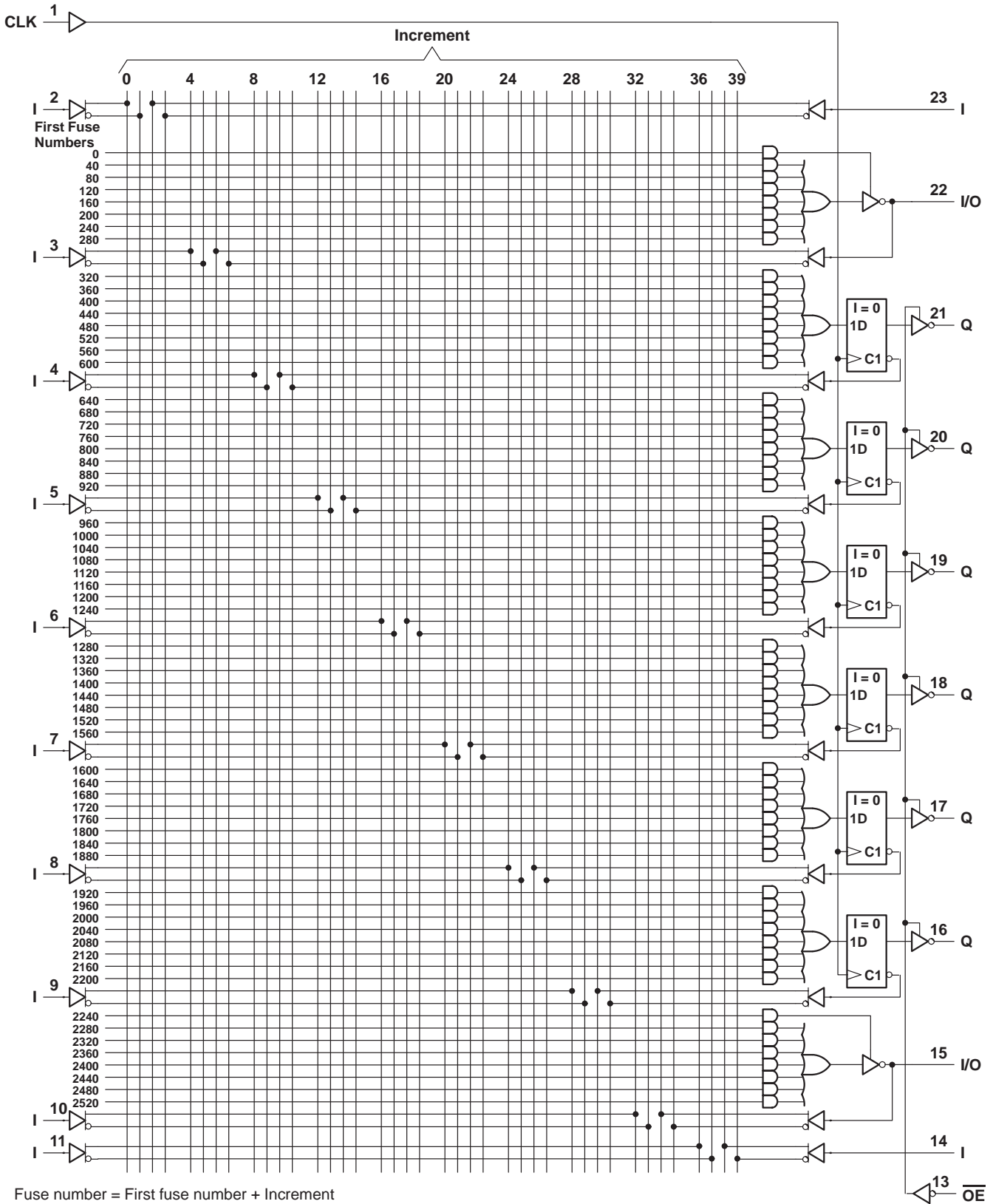


Fuse number = First fuse number + Increment
Pin numbers shown are for JT and NT packages.

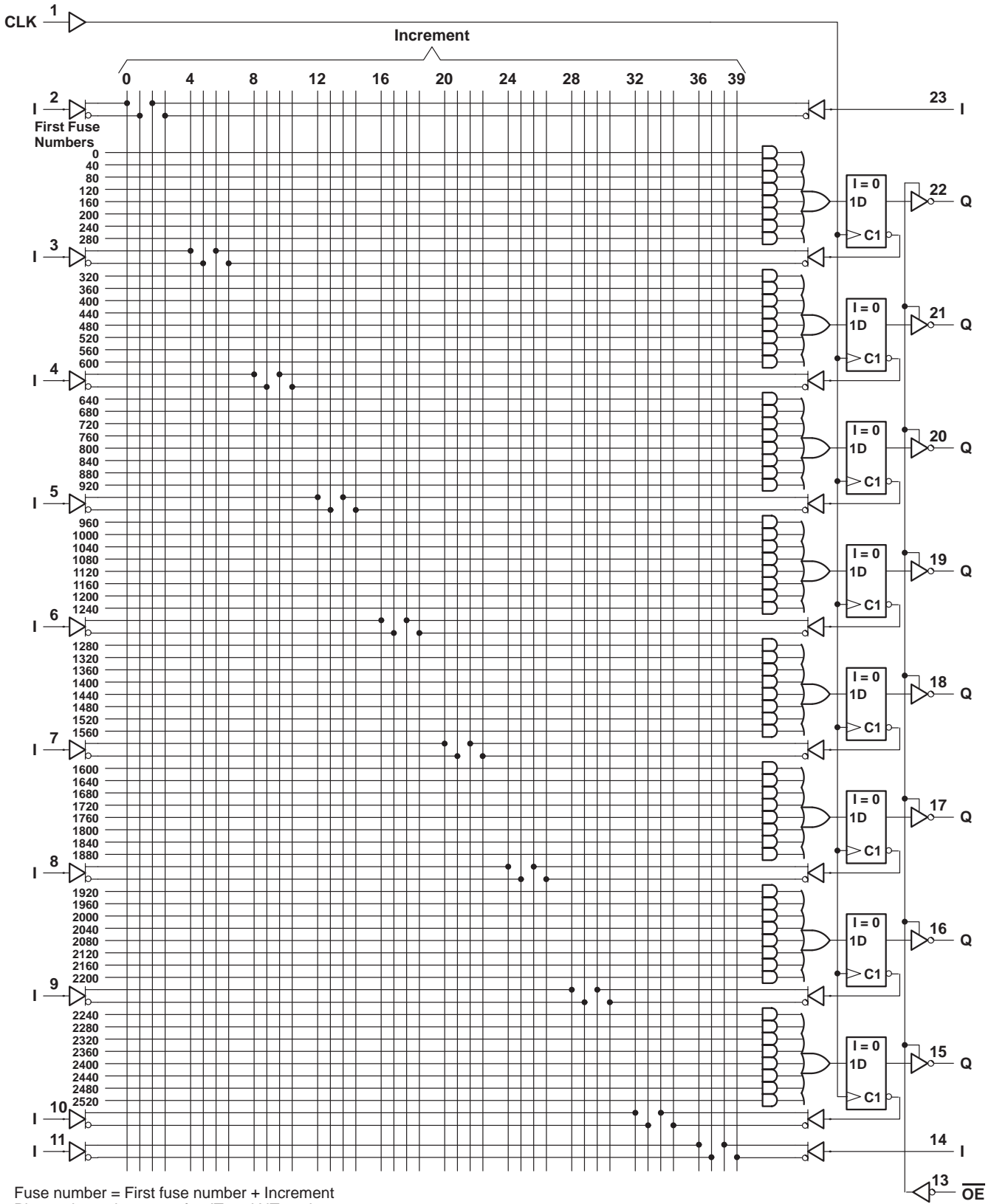
logic diagram (positive logic)



logic diagram (positive logic)



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage (see Note 1)	5.5 V
Voltage applied to disabled output (see Note 1)	5.5 V
Operating free-air temperature range	0°C to 75°C
Storage temperature range	–65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle or during a preload cycle.

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.75	5	5.25	V
V_{IH}	High-level input voltage (see Note 2)	2		5.5	V
V_{IL}	Low-level input voltage (see Note 2)			0.8	V
I_{OH}	High-level output current			–3.2	mA
I_{OL}	Low-level output current			24	mA
T_A	Operating free-air temperature	0	25	75	°C

NOTE 2: These are absolute voltage levels with respect to the ground pin of the device and include all overshoots due to system and/or tester noise. Testing these parameters should not be attempted without suitable equipment.

electrical characteristics over recommended operating free-air temperature range

PARAMETER	TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{IK}	$V_{CC} = 4.75$ V,	$I_I = -18$ mA		–0.8	–1.5	V
V_{OH}	$V_{CC} = 4.75$ V,	$I_{OH} = -3.2$ mA	2.4	2.7		V
V_{OL}	$V_{CC} = 4.75$ V,	$I_{OL} = 24$ mA		0.3	0.5	V
$I_{OZH}‡$	$V_{CC} = 5.25$ V,	$V_O = 2.7$ V			100	μA
$I_{OZL}‡$	$V_{CC} = 5.25$ V,	$V_O = 0.4$ V			–100	μA
I_I	$V_{CC} = 5.25$ V,	$V_I = 5.5$ V			100	μA
$I_{IH}‡$	$V_{CC} = 5.25$ V,	$V_I = 2.7$ V			25	μA
$I_{IL}‡$	$V_{CC} = 5.25$ V,	$V_I = 0.4$ V			–250	μA
$I_{OS}§$	$V_{CC} = 5.25$ V,	$V_O = 0.5$ V	–30	–70	–130	mA
I_{CC}	$V_{CC} = 5.25$ V,	$V_I = 0$, Outputs open			210	mA
C_i	$f = 1$ MHz,	$V_I = 2$ V		8.5		pF
C_o	$f = 1$ MHz,	$V_O = 2$ V		10		pF

† All typical values are at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$.

‡ I/O leakage is the worst case of I_{OZL} and I_{IL} or I_{OZH} and I_{IH} , respectively.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. V_O is set at 0.5 V to avoid test problems caused by test equipment ground degradation.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)		TEST CONDITIONS	TIBPAL20L8-5CFN		TIBPAL20L8-5CJT TIBPAL20L8-5CNT		UNIT
					MIN	MAX	MIN	MAX	
t_{pd}	I, I/O	O, I/O	with up to 4 outputs switching	R1 = 200 Ω, R2 = 200 Ω, See Figure 8	1.5	5	1.5	5	ns
	I, I/O	O, I/O	with more than 4 outputs switching		1.5	5	1.5	5.5	
t_{en}	I, I/O	O, I/O			2	7	2	7	ns
t_{dis}	I, I/O	O, I/O			2	7	2	7	ns

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



TIBPAL20R4-5C, TIBPAL20R6-5C HIGH-PERFORMANCE *IMPACT-X*™ PAL® CIRCUITS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage (see Note 1)	5.5 V
Voltage applied to disabled output (see Note 1)	5.5 V
Operating free-air temperature range	0°C to 75°C
Storage temperature range	–65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle or during a preload cycle.

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.75	5	5.25	V
V_{IH}	High-level input voltage (see Note 2)	2		5.5	V
V_{IL}	Low-level input voltage (see Note 2)			0.8	V
I_{OH}	High-level output current			–3.2	mA
I_{OL}	Low-level output current			24	mA
f_{clock}	Clock frequency	0		125	MHz
t_w	Pulse duration, clock	High	4		ns
		Low	4		
t_{su}	Setup time, input or feedback before clock↑	4.5		ns	
t_h	Hold time, input or feedback after clock↑	0		ns	
T_A	Operating free-air temperature	0	25	75	°C

NOTE 2: These are absolute voltage levels with respect to the ground pin of the device and include all overshoots due to system and/or tester noise. Testing these parameters should not be attempted without suitable equipment.

TIBPAL20R4-5C, TIBPAL20R6-5C HIGH-PERFORMANCE *IMPACT-X*TM PAL[®] CIRCUITS

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electrical characteristics over recommended operating free-air temperature range

PARAMETER		TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
V _{IK}		V _{CC} = 4.75 V,	I _I = -18 mA		-0.8	-1.5	V
V _{OH}		V _{CC} = 4.75 V,	I _{OH} = -3.2 mA	2.4	2.7		V
V _{OL}		V _{CC} = 4.75 V,	I _{OL} = 24 mA		0.3	0.5	V
I _{OZH} [‡]		V _{CC} = 5.25 V,	V _O = 2.7 V			100	μA
I _{OZL} [‡]		V _{CC} = 5.25 V,	V _O = 0.4 V			-100	μA
I _I		V _{CC} = 5.25 V,	V _I = 5.5 V			100	μA
I _{IH} [‡]		V _{CC} = 5.25 V,	V _I = 2.7 V			25	μA
I _{IL} [‡]		V _{CC} = 5.25 V,	V _I = 0.4 V			-250	μA
I _{OS} [§]		V _{CC} = 5.25 V,	V _O = 0.5 V	-30	-70	-130	mA
I _{CC}		V _{CC} = 5.25 V,	V _I = 0, Outputs open			210	mA
C _i	I	f = 1 MHz,	V _I = 2 V	8.5			pF
	CLK/OE			7.5			
C _o	I/O	f = 1 MHz,	V _O = 2 V	10			pF
	Q			7			

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	TIBPAL20R4-5CFN TIBPAL20R6-5CFN			TIBPAL20R4-5CJT TIBPAL20R4-5CNT TIBPAL20R6-5CJT TIBPAL20R6-5CNT			UNIT
				MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	
f _{max} [¶]	without feedback		R1 = 200 Ω, R2 = 200 Ω, See Figure 8	125			125			MHz
	with internal feedback (counter configuration)			125			125			
	with external feedback			117			111			
t _{pd}	CLK↑	Q		1.5			4.5			ns
t _{pd}	CLK↑	Internal feedback		3.5			3.5			ns
t _{pd}	I, I/O	I/O		1.5			5			ns
t _{en}	\overline{OE} ↓	Q		1.5			6			ns
t _{dis}	\overline{OE} ↑	Q		1			7			ns
t _{en}	I, I/O	I/O		2			7			ns
t _{dis}	I, I/O	I/O		2			7			ns
t _r			1.5			1.5			ns	
t _f			1.5			1.5			ns	
t _{sk(o)} [#]	Skew between registered outputs		0.5			0.5			ns	

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.

[‡] I/O leakage is the worst case of I_{OZL} and I_{IL} or I_{OZH} and I_{IH}, respectively.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. V_O is set at 0.5 V to avoid test problems caused by test equipment ground degradation.

[¶] See 'f_{max} Specification' near the end of this data sheet.

[#] t_{sk(o)} is the skew time between registered outputs.

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TIBPAL20R8-5C HIGH-PERFORMANCE *IMPACT-X*™ *PAL*® CIRCUITS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage (see Note 1)	5.5 V
Voltage applied to disabled output (see Note 1)	5.5 V
Operating free-air temperature range	0°C to 75°C
Storage temperature range	–65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle or during a preload cycle.

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.75	5	5.25	V
V_{IH}	High-level input voltage (see Note 2)	2		5.5	V
V_{IL}	Low-level input voltage (see Note 2)			0.8	V
I_{OH}	High-level output current			–3.2	mA
I_{OL}	Low-level output current			24	mA
f_{clock}	Clock frequency	0		125	MHz
t_w	Pulse duration, clock	High	4		ns
		Low	4		
t_{su}	Setup time, input or feedback before clock↑	4.5			ns
t_h	Hold time, input or feedback after clock↑	0			ns
T_A	Operating free-air temperature	0	25	75	°C

NOTE 2: These are absolute voltage levels with respect to the ground pin of the device and include all overshoots due to system and/or tester noise. Testing these parameters should not be attempted without suitable equipment.

electrical characteristics over recommended operating free-air temperature range

PARAMETER	TEST CONDITIONS	TIBPAL20R8-5CFN			TIBPAL20R8-5CJT TIBPAL20R8-5CNT			UNIT
		MIN	TYP†	MAX	MIN	TYP†	MAX	
V _{IK}	V _{CC} = 4.75 V, I _I = -18 mA	-0.8	-1.5		-0.8	-1.5		V
V _{OH}	V _{CC} = 4.75 V, I _{OH} = -3.2 mA	2.4	2.7		2.4	2.7		V
V _{OL}	V _{CC} = 4.75 V, I _{OL} = 24 mA		0.3	0.5		0.3	0.5	V
I _{OZH}	V _{CC} = 5.25 V, V _O = 2.7 V			100			100	μA
I _{OZL}	V _{CC} = 5.25 V, V _O = 0.4 V			-100			-100	μA
I _I	V _{CC} = 5.25 V, V _I = 5.5 V			100			100	μA
I _{IH}	V _{CC} = 5.25 V, V _I = 2.7 V			25			25	μA
I _{IL}	V _{CC} = 5.25 V, V _I = 0.4 V			-250			-250	μA
I _{OS‡}	V _{CC} = 5.25 V, V _O = 0.5 V	-30	-70	-130	-30	-70	-130	mA
I _{CC}	V _{CC} = 5.25 V, V _I = 0, Outputs open			210			210	mA
C _i	f = 1 MHz, V _I = 2 V	I			6.5			pF
		CLK/OE			5.5			
C _o	f = 1 MHz, V _O = 2 V	10			8			pF

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	TIBPAL20R8-5CFN			TIBPAL20R8-5CJT TIBPAL20R8-5CNT			UNIT
				MIN	TYP†	MAX	MIN	TYP†	MAX	
f _{max} §	without feedback		R1 = 200 Ω, R2 = 200 Ω, See Figure 8	125			125			MHz
	with internal feedback (counter configuration)			125			125			
	with external feedback			117			111			
t _{pd}	CLK↑	Q		with up to 4 outputs switching	1.5	4		1.5	4	ns
	CLK↑	Q		with more than 4 outputs switching	1.5	4		1.5	4.5	
t _{pd} ¶	CLK↑	Internal feedback		3.5			3.5			ns
t _{en}	OE↓	Q		1.5	6		1.5	6	ns	
t _{dis}	OE↑	Q		1	6.5		1	7	ns	
t _r				1.5			1.5			ns
t _f				1.5			1.5			ns
t _{sk(o)} #	Skew between outputs			0.5			0.5			ns

† All typical values are at V_{CC} = 5 V, T_A = 25°C.

‡ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. V_O is set at 0.5 V to avoid test problems caused by test equipment ground degradation.

§ See 'f_{max} Specification' near the end of this data sheet.

¶ This parameter is calculated from the measured f_{max} with internal feedback in a counter configuration (see Figure 4 for illustration).

t_{sk(o)} is the skew time between registered outputs.

TIBPAL20L8-7M, TIBPAL20R4-7M, TIBPAL20R6-7M, TIBPAL20R8-7M HIGH-PERFORMANCE *IMPACT-X*™ *PAL*® CIRCUITS

SRPS010F – D3353, OCTOBER 1989 – REVISED SEPTEMBER 1992

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage (see Note 1)	5.5 V
Voltage applied to disabled output (see Note 1)	5.5 V
Operating free-air temperature range	–55°C to 125°C
Storage temperature range	–65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle or during a preload cycle.

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage (see Note 2)	2		5.5	V
V_{IL}	Low-level input voltage (see Note 2)			0.8	V
I_{OH}	High-level output current			–2	mA
I_{OL}	Low-level output current			12	mA
f_{clock}^\dagger	Clock frequency	0		100	MHz
t_w^\dagger	Pulse duration, clock	High		5	ns
		Low		5	
t_{su}^\dagger	Setup time, input or feedback before clock \uparrow	7			ns
t_h^\dagger	Hold time, input or feedback after clock \uparrow	0			ns
T_A	Operating free-air temperature	–55	25	125	°C

$^\dagger f_{clock}$, t_w , t_{su} , and t_h do not apply to TIBPAL16L8'

NOTE 2: These are absolute voltage levels with respect to the ground pin of the device and include all overshoots due to system and/or tester noise. Testing these parameters should not be attempted without suitable equipment.

PRODUCT PREVIEW

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



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TIBPAL20L8-7M, TIBPAL20R4-7M, TIBPAL20R6-7M, TIBPAL20R8-7M HIGH-PERFORMANCE *IMPACT-X*TM PAL[®] CIRCUITS

SRPS010F – D3353, OCTOBER 1989 – REVISED SEPTEMBER 1992

electrical characteristics over recommended operating free-air temperature range

PARAMETER		TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V _{IK}		V _{CC} = 4.5 V,	I _I = -18 mA		-0.8	-1.5	V
V _{OH}		V _{CC} = 4.5 V,	I _{OH} = -2 mA	2.4	2.7		V
V _{OL}		V _{CC} = 4.5 V,	I _{OL} = 12 mA		0.25	0.5	V
I _{OZH}	0, Q outputs	V _{CC} = 5.5 V,	V _O = 2.7 V			20	μA
	I/O ports					100	
I _{OZL}	0, Q outputs	V _{CC} = 5.5 V,	V _O = 0.4 V			-20	μA
	I/O ports					-250	
I _I		V _{CC} = 5.5 V,	V _I = 5.5 V			1	mA
I _{IH}	I/O ports	V _{CC} = 5.5 V,	V _I = 2.7 V			100	μA
	All others					25	
I _{IL}		V _{CC} = 5.5 V,	V _I = 0.4 V			-250	μA
I _{OS‡}		V _{CC} = 5.5 V,	V _O = 0.5 V	-30	-70	-130	mA
I _{CC}		V _{CC} = 5.5 V,	V _I = GND, $\overline{OE} = V_{IH}$, Outputs open			220	mA
C _i	I	f = 1 MHz,	V _I = 2 V			8.5	pF
	CLK/ \overline{OE}					7.5	
C _o		f = 1 MHz,	V _O = 2 V			10	pF

† All typical values are at V_{CC} = 5 V, T_A = 25°C.

‡ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second. V_O is set at 0.5 V to avoid test problems caused by test equipment ground degradation.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITION	MIN	MAX	UNIT
f _{max} §	without feedback		R1 = 390 Ω, R2 = 750 Ω, See Figure 8	100		MHz
	with internal feedback (counter configuration)			100		
	with external feedback			74		
t _{pd}	I, I/O	O, I/O		1	7	ns
t _{pd}	CLK	Q		1	7	ns
t _{en}	OE↓	Q		1	8	ns
t _{dis}	OE↑	Q	1	10	ns	
t _{en}	I, I/O	O, I/O	1	9	ns	
t _{dis}	I, I/O	O, I/O	1	10	ns	

§ See 'f_{max} Specification' near the end of this data sheet. f_{max} does not apply for TIBPAL20L8'. f_{max} with external feedback is not production tested and is calculated from the equation found in the f_{max} specifications section.

PRODUCT PREVIEW

programming information

Texas Instruments programmable logic devices can be programmed using widely available software and inexpensive device programmers.

Complete programming specifications, algorithms, and the latest information on hardware, software, and firmware are available upon request. Information on programmers capable of programming Texas Instruments programmable logic is also available, upon request, from the nearest TI field sales office, local authorized TI distributor, or by calling Texas Instruments at (214) 997-5666.

asynchronous preload procedure for registered outputs (see Figure 1 and Note 3)

The output registers can be preloaded to any desired state during device testing. This permits any state to be tested without having to step through the entire state-machine sequence. Each register is preloaded individually by following the steps given below.

- Step 1. With V_{CC} at 5 volts and Pin 1 at V_{IL} , raise Pin 13 to V_{IHH} .
- Step 2. Apply either V_{IL} or V_{IH} to the output corresponding to the register to be preloaded.
- Step 3. Lower Pin 13 to 5 V.
- Step 4. Remove output voltage, then lower Pin 13 to V_{IL} . Preload can be verified by observing the voltage level at the output pin.

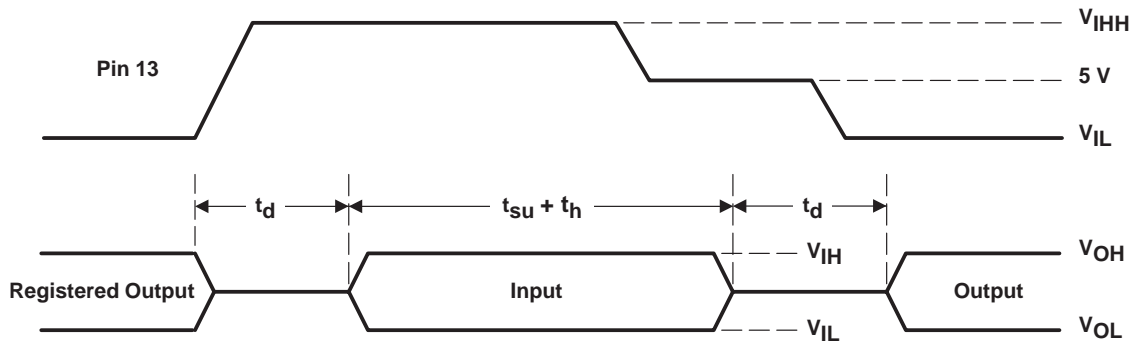
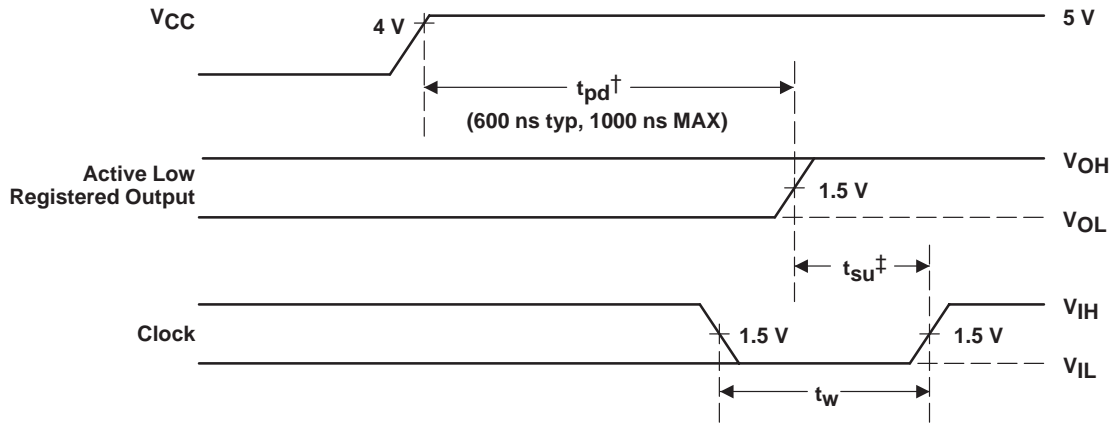


Figure 1. Asynchronous Preload Waveforms

NOTE 3: $t_d = t_{su} = t_h = 100$ ns to 1000 ns, $V_{IHH} = 10.25$ V to 10.75 V

power-up reset, see Figure 2

Following power up, all registers are reset to zero. This feature provides extra flexibility to the system designer and is especially valuable in simplifying state-machine initialization. To ensure a valid power-up reset, it is important that the rise of V_{CC} be monotonic. Following power-up reset, a low-to-high clock transition must not occur until all applicable input and feedback setup times are met.



† This is the power-up reset time and applies to registered outputs only. The values shown are from characterization data.

‡ This is the setup time for input or feedback.

Figure 2. Power-Up Reset Waveforms

f_{max} SPECIFICATIONS

f_{max} without feedback, see Figure 3

In this mode, data is presented at the input to the flip-flop and clocked through to the Q output with no feedback. Under this condition, the clock period is limited by the sum of the data setup time and the data hold time (t_{su} + t_h). However, the minimum f_{max} is determined by the minimum clock period (t_w high + t_w low).

$$\text{Thus, } f_{\text{max}} \text{ without feedback} = \frac{1}{(t_{w\text{high}} + t_{w\text{low}})} \text{ or } \frac{1}{(t_{\text{su}} + t_{\text{h}})}$$

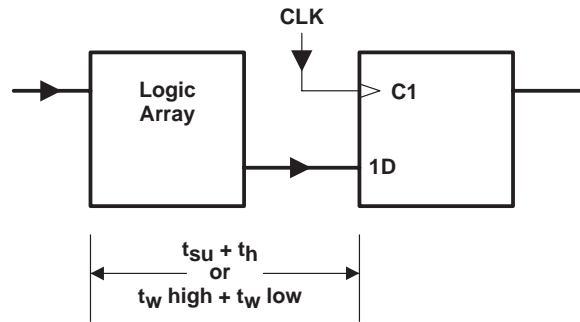


Figure 3. f_{max} Without Feedback

f_{max} with internal feedback, see Figure 4

This configuration is most popular in counters and on-chip state-machine designs. The flip-flop inputs are defined by the device inputs and flip-flop outputs. Under this condition, the period is limited by the internal delay from the flip-flop outputs through the internal feedback and logic array to the inputs of the next flip-flop.

$$\text{Thus, } f_{\text{max}} \text{ with internal feedback} = \frac{1}{(t_{\text{su}} + t_{\text{pd CLK-to-FB}})}$$

Where t_{pd} CLK-to-FB is the deduced value of the delay from CLK to the input of the logic array.

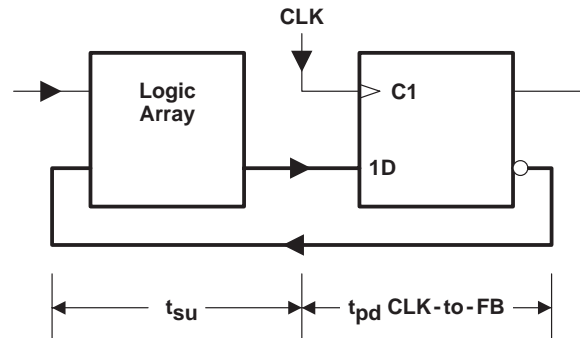


Figure 4. f_{max} With Internal Feedback

f_{max} SPECIFICATIONS

f_{max} with external feedback, see Figure 5

This configuration is a typical state-machine design with feedback signals sent off-chip. This external feedback could go back to the device inputs or to a second device in a multi-chip state machine. The slowest path defining the period is the sum of the clock-to-output time and the input setup time for the external signals (t_{su} + t_{pd} CLK-to-Q).

$$\text{Thus, } f_{\text{max}} \text{ with external feedback} = \frac{1}{(t_{\text{su}} + t_{\text{pd}} \text{ CLK-to-Q})}$$

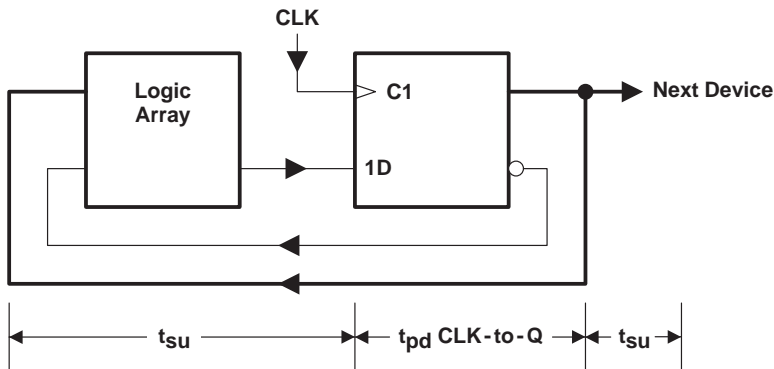


Figure 5. f_{max} With External Feedback

THERMAL INFORMATION

thermal management of the TIBPAL20R8-5C

Thermal management of the TIBPAL20R8-5CNT and TIBPAL20R8-5CFN is necessary when operating at certain conditions of frequency, output loading, and outputs switching simultaneously. The device and system application will determine the appropriate level of management.

Determining the level of thermal management is based on factors such as power dissipation (P_D), ambient temperature (T_A), and transverse airflow (FPM). Figures 6 (a) and 6 (b) show the relationship between ambient temperature and transverse airflow at given power dissipation levels. The required transverse airflow can be determined at a particular ambient temperature and device power dissipation level in order to ensure the device specifications.

Figure 7 illustrates how power dissipation varies as a function of frequency and the number of outputs switching simultaneously. It should be noted that all outputs are fully loaded ($C_L = 50$ pF). Since the condition of eight fully loaded outputs represents the worst-case condition, each application must be evaluated accordingly.

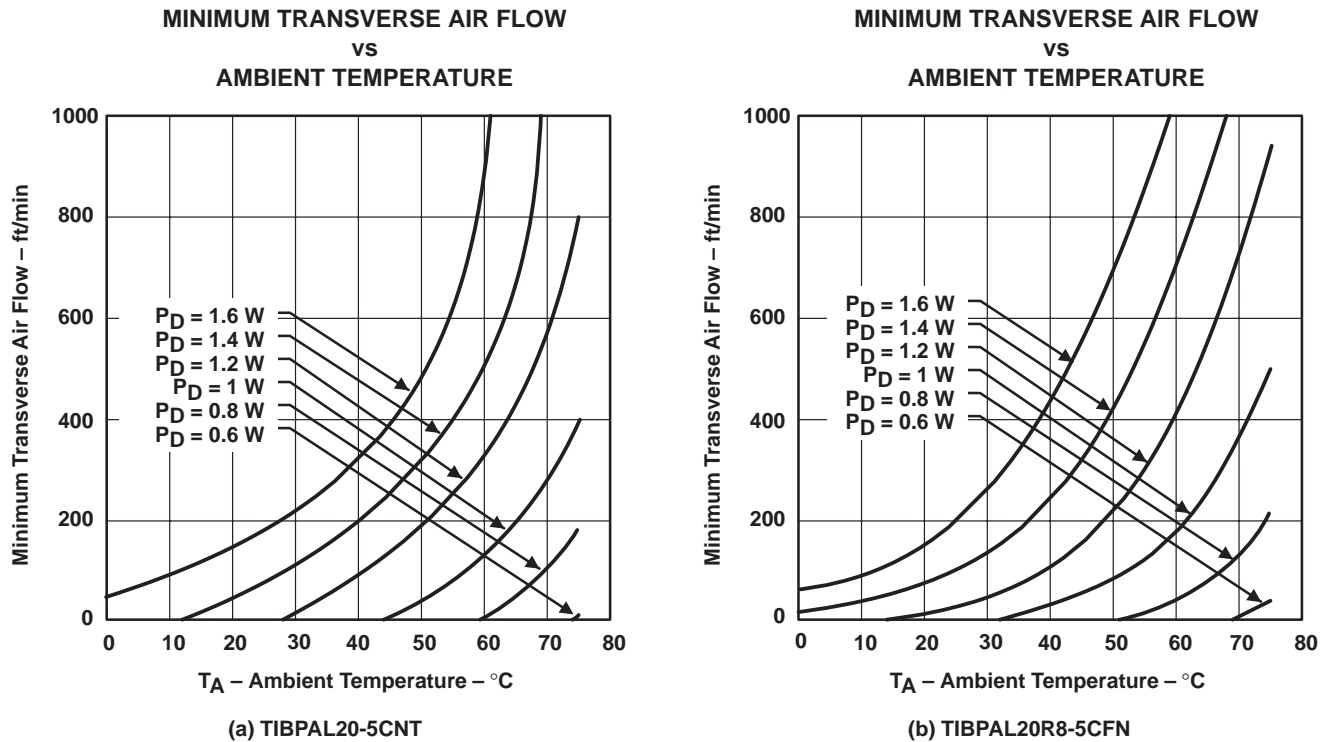


Figure 6

THERMAL INFORMATION

**POWER DISSIPATION
 vs
 FREQUENCY**

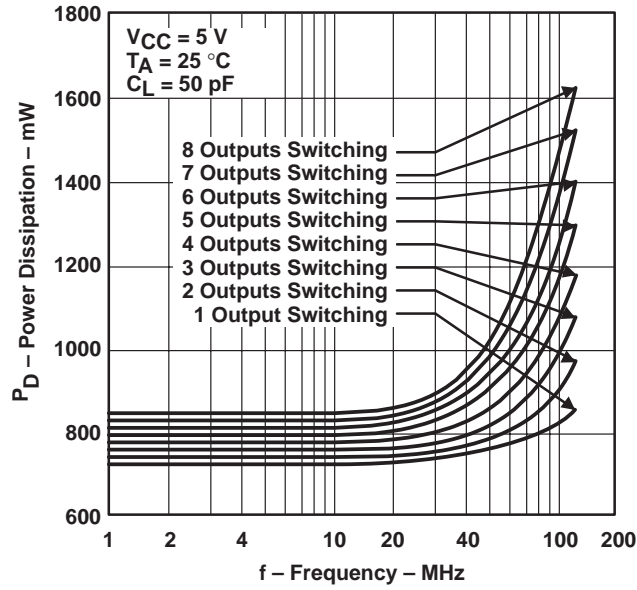
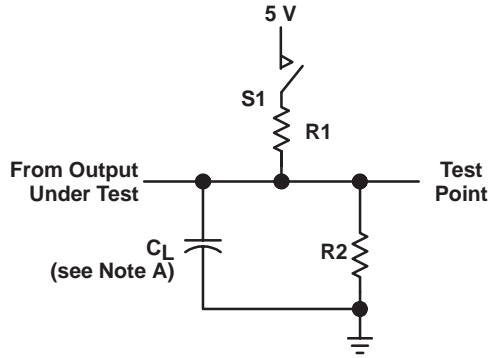
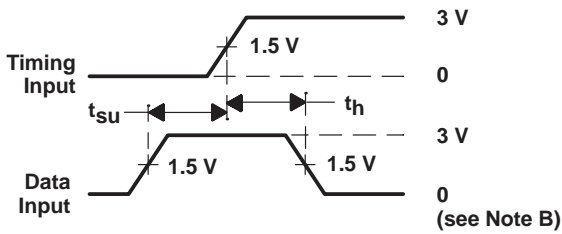


Figure 7

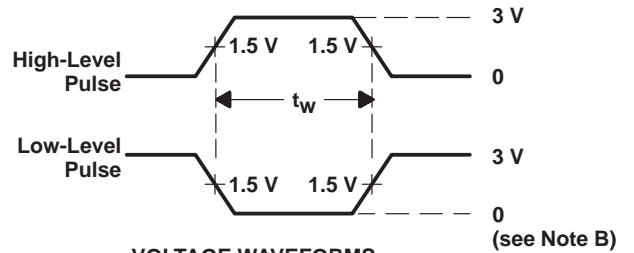
PARAMETER MEASUREMENT INFORMATION



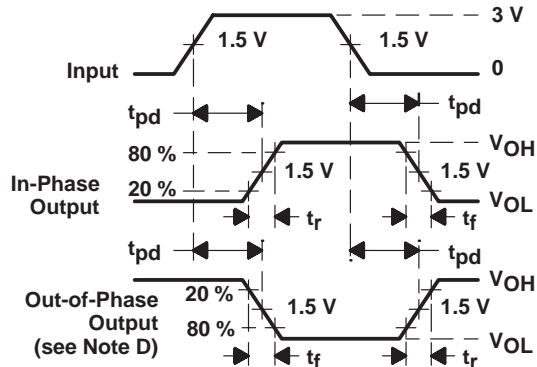
LOAD CIRCUIT FOR 3-STATE OUTPUTS



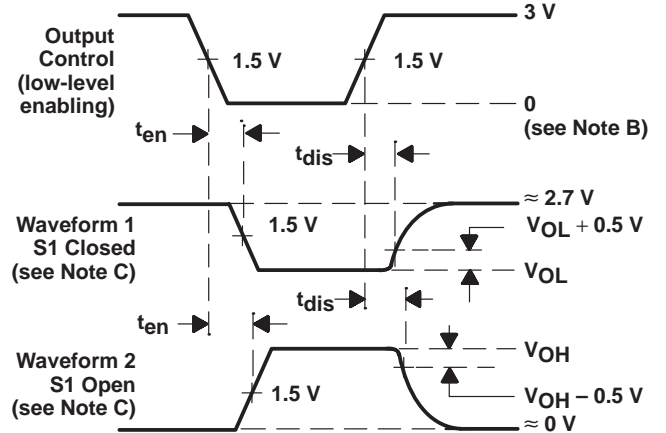
VOLTAGE WAVEFORMS SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS PULSE DURATIONS



VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

- NOTES: A. C_L includes probe and jig capacitance and is 50 pF for t_{pd} and t_{en} , 5 pF for t_{dis} .
 B. All input pulses have the following characteristics: For C suffix, $PRR \leq 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%; For M suffix, $PRR \leq 10$ MHz, $t_r = t_f \leq 2$ ns, duty cycle = 50%.
 C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 D. When measuring propagation delay times of 3-state outputs, switch S1 is closed.
 E. Equivalent loads may be used for testing.

Figure 8. Load Circuit and Voltage Waveforms

metastable characteristics of TIBPAL20R4-5C, TIBPAL20R6-5C, and TIBPAL20R8-5C

At some point a system designer is faced with the problem of synchronizing two digital signals operating at two different frequencies. This problem is typically overcome by synchronizing one of the signals to the local clock through use of a flip-flop. However, this solution presents an awkward dilemma since the setup and hold time specifications associated with the flip-flop are sure to be violated. The metastable characteristics of the flip-flop can influence overall system reliability.

Whenever the setup and hold times of a flip-flop are violated, its output response becomes uncertain and is said to be in the metastable state if the output hangs up in the region between V_{IL} and V_{IH} . This metastable condition lasts until the flip-flop falls into one of its two stable states, which takes longer than the specified maximum propagation delay time (CLK to Q max).

From a system engineering standpoint, a designer cannot use the specified data sheet maximum for propagation delay time when using the flip-flop as a data synchronizer – how long to wait after the specified data sheet maximum must be known before using the data in order to guarantee reliable system operation.

The circuit shown in Figure 9 can be used to evaluate MTBF (Mean Time Between Failure) and Δt for a selected flip-flop. Whenever the Q output of the DUT is between 0.8 V and 2 V, the comparators are in opposite states. When the Q output of the DUT is higher than 2 V or lower than 0.8 V, the comparators are at the same logic level. The outputs of the two comparators are sampled a selected time (Δt) after SCLK. The exclusive OR gate detects the occurrence of a failure and increments the failure counter.

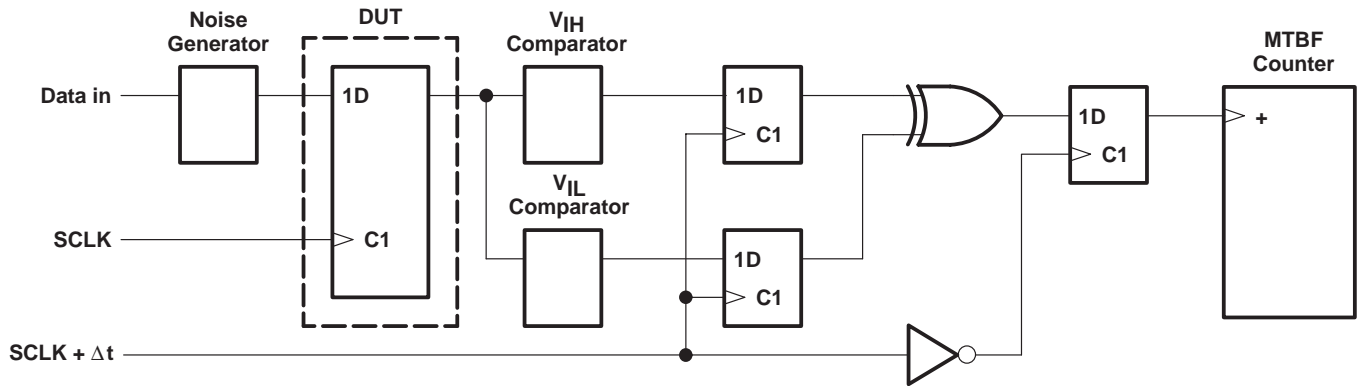


Figure 9. Metastable Evaluation Test Circuit

In order to maximize the possibility of forcing the DUT into a metastable state, the input data signal is applied so that it always violates the setup and hold time. This condition is illustrated in the timing diagram in Figure 10. Any other relationship of SCLK to data will provide less chance for the device to enter into the metastable state.

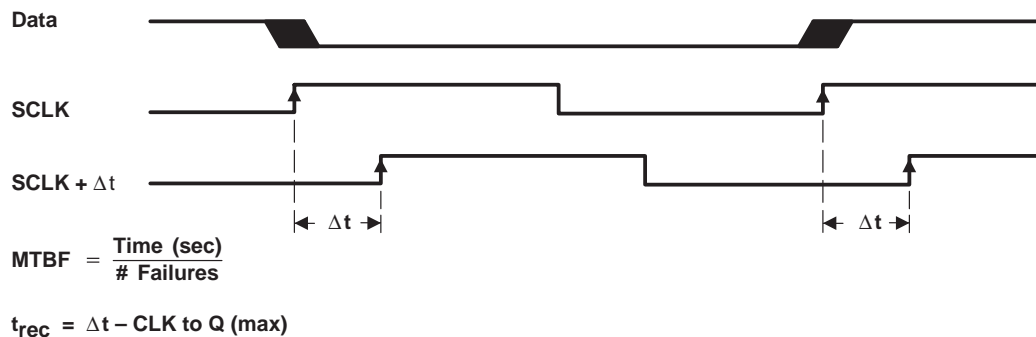


Figure 10. Timing Diagram

By using the described test circuit, MTBF can be determined for several different values of Δt (see Figure 9). Plotting this information on semilog scale demonstrates the metastable characteristics of the selected flip-flop. Figure 11 shows the results for the TIBPAL20'-5C operating at 1 MHz.

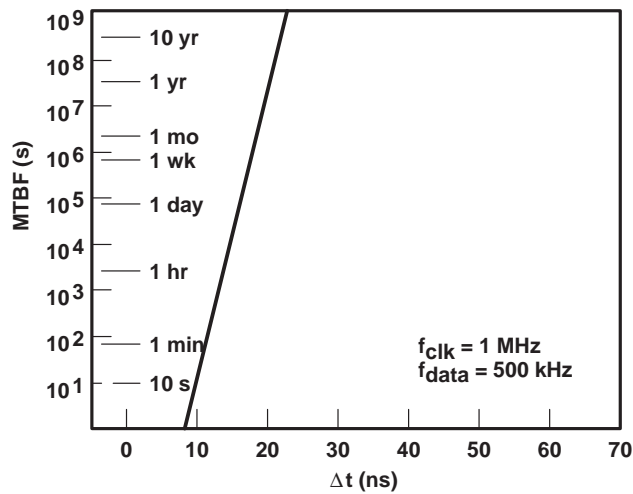


Figure 11. Metastable Characteristics

From the data taken in the above experiment, an equation can be derived for the metastable characteristics at other clock frequencies.

The metastable equation: $\frac{1}{\text{MTBF}} = f_{\text{SCLK}} \times f_{\text{data}} \times C1 \times e^{-C2 \times \Delta t}$

The constants C1 and C2 describe the metastable characteristics of the device. From the experimental data, these constants can be solved for: $C1 = 4.37 \times 10^{-3}$ and $C2 = 2.01$

Therefore

$$\frac{1}{\text{MTBF}} = f_{\text{SCLK}} \times f_{\text{data}} \times 4.37 \times 10^{-3} \times e^{-2.01 \times \Delta t}$$

definition of variables

DUT (Device Under Test): The DUT is a 5-ns registered PLD programmed with the equation $Q := D$.

MTBF (Mean Time Between Failures): The average time (s) between metastable occurrences that cause a violation of the device specifications.

f_{SCLK} (system clock frequency): Actual clock frequency for the DUT.

f_{data} (data frequency): Actual data frequency for a specified input to the DUT.

C1: Calculated constant that defines the magnitude of the curve.

C2: Calculated constant that defines the slope of the curve.

t_{rec} (metastability recovery time): Minimum time required to guarantee recovery from metastability, at a given MTBF failure rate. $t_{\text{rec}} = \Delta t - t_{\text{pd}}$ (CLK to Q, max)

Δt : The time difference (ns) from when the synchronizing flip-flop is clocked to when its output is sampled.

The test described above has shown the metastable characteristics of the TIBPAL20R4/R6/R8-5C series. For additional information on metastable characteristics of Texas Instruments logic circuits, please refer to TI Applications publication SDAA004, "Metastable Characteristics, Design Considerations for ALS, AS, and LS Circuits."

TYPICAL CHARACTERISTICS

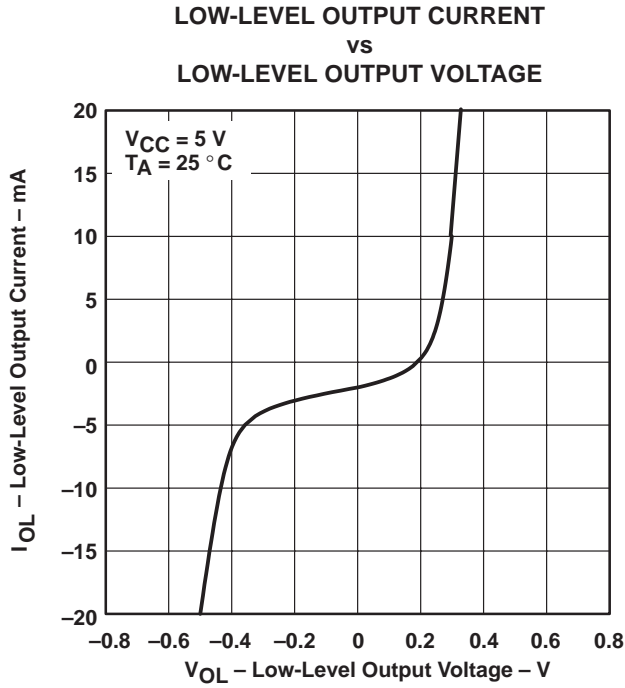


Figure 12

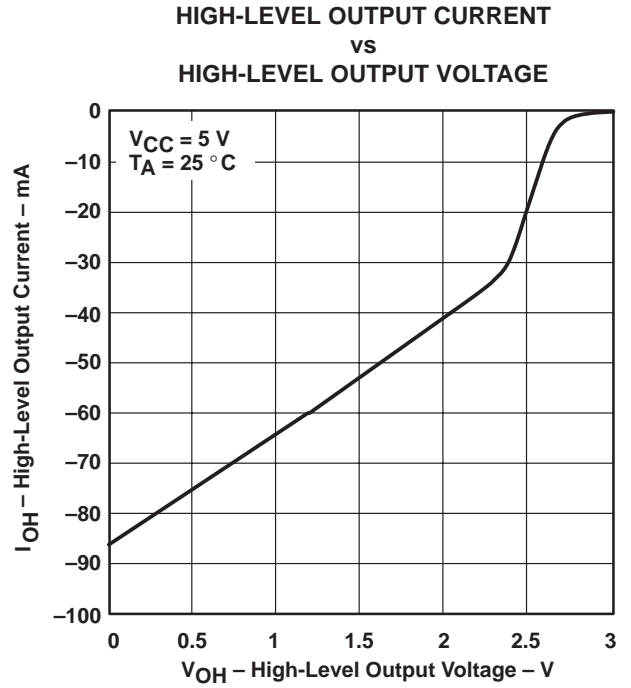


Figure 13

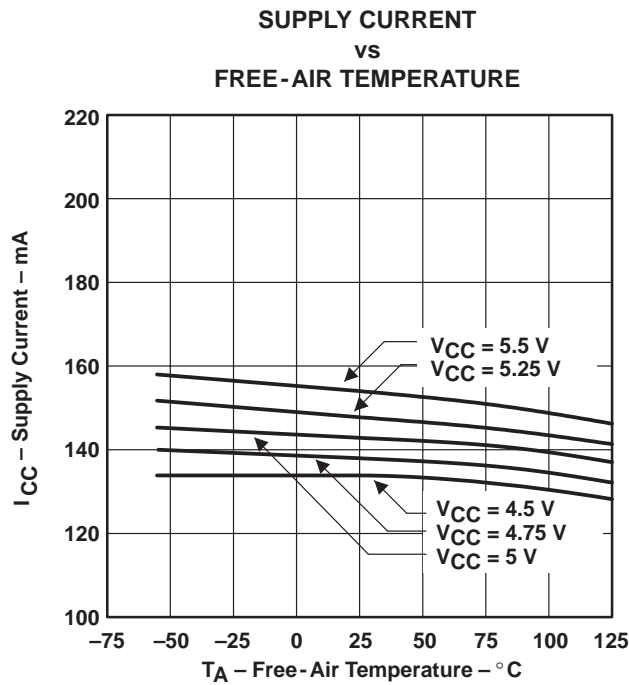


Figure 14

TYPICAL CHARACTERISTICS

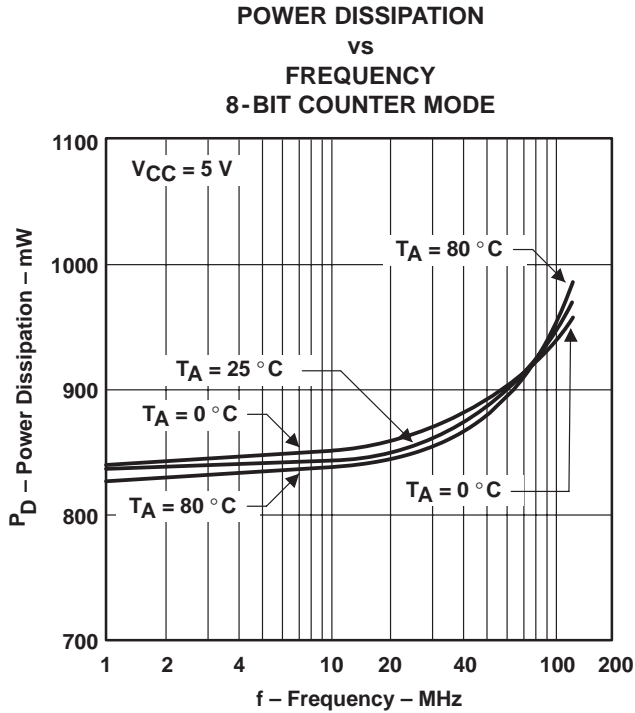


Figure 15

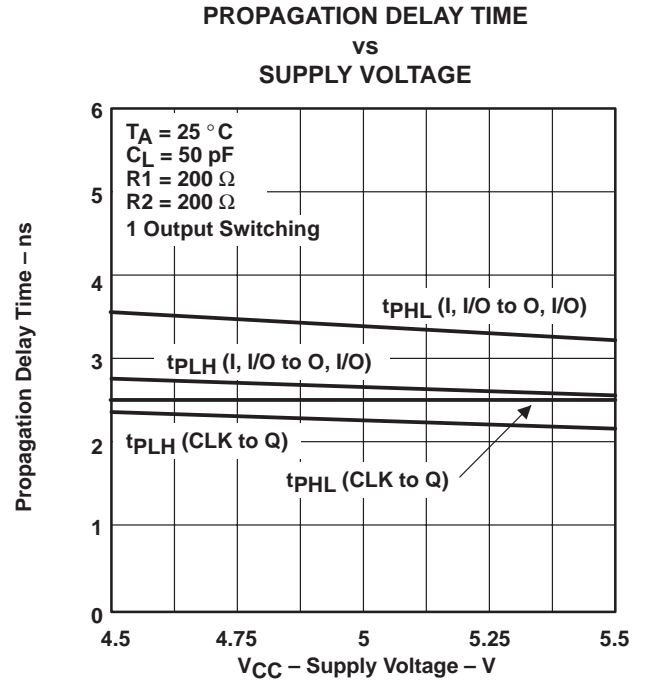


Figure 16

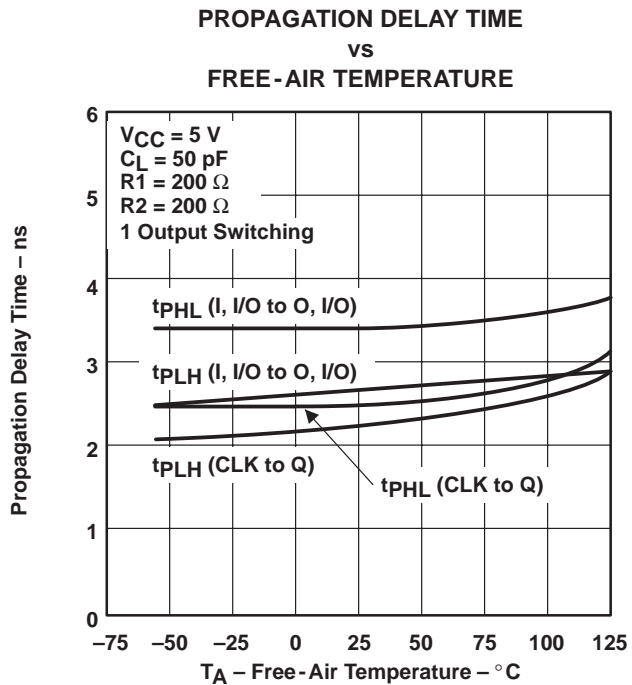


Figure 17

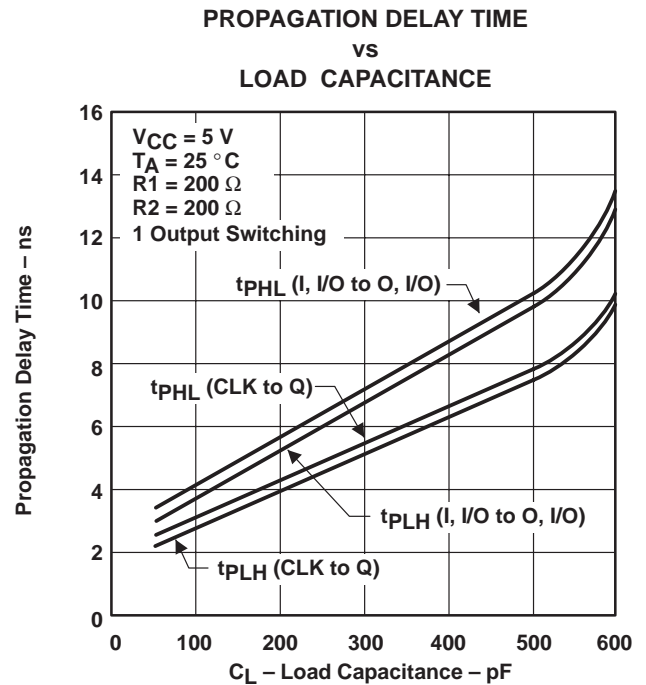


Figure 18

TYPICAL CHARACTERISTICS

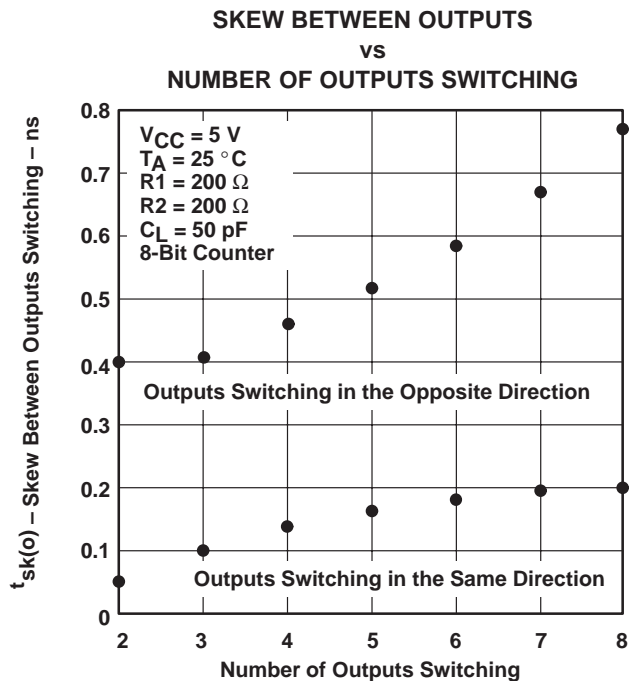


Figure 19

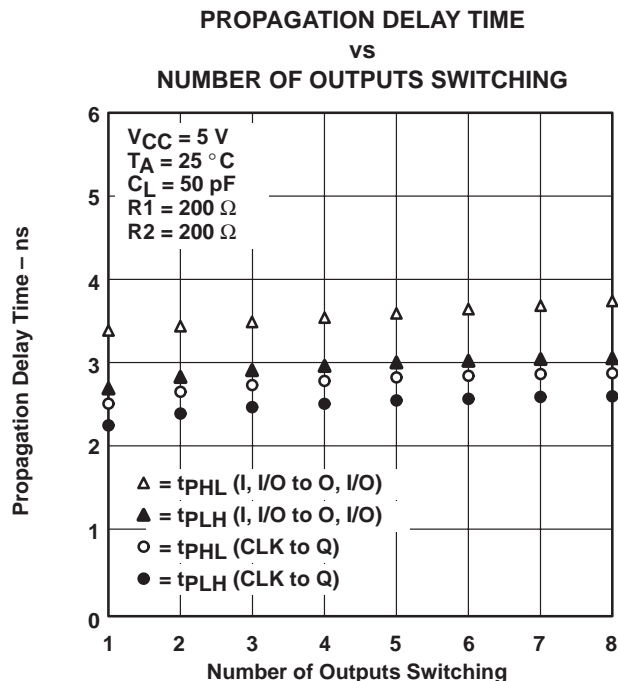


Figure 20

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